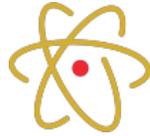


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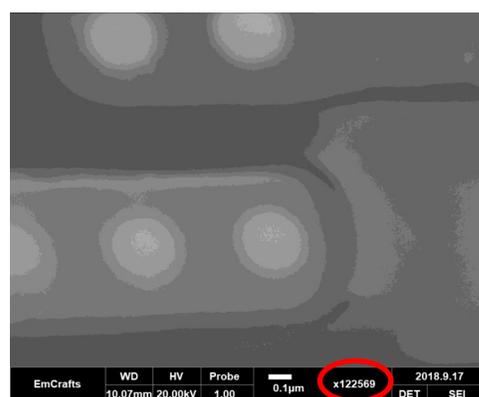
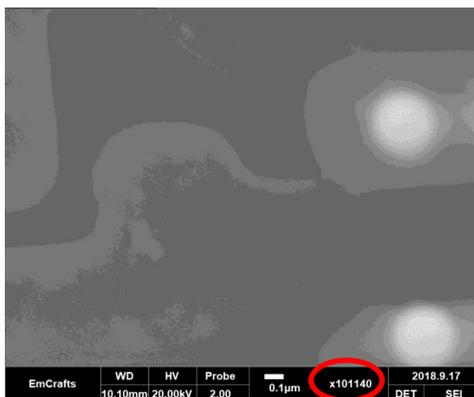
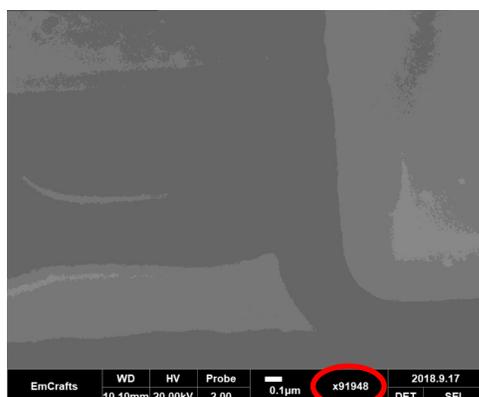
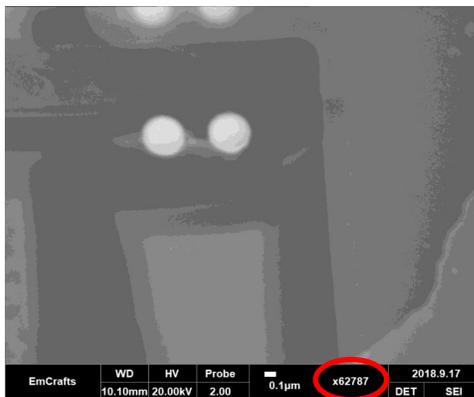
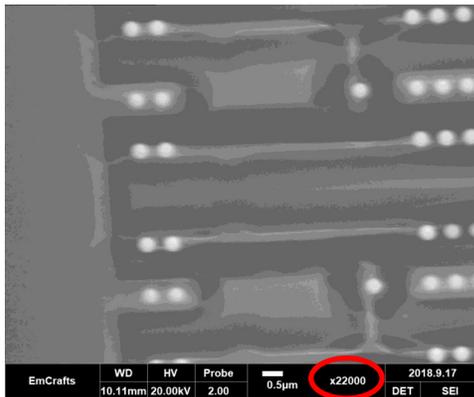
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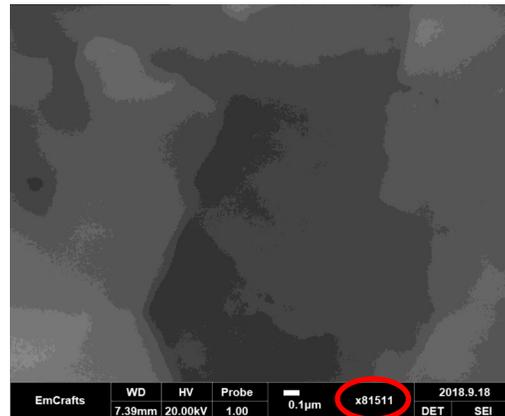
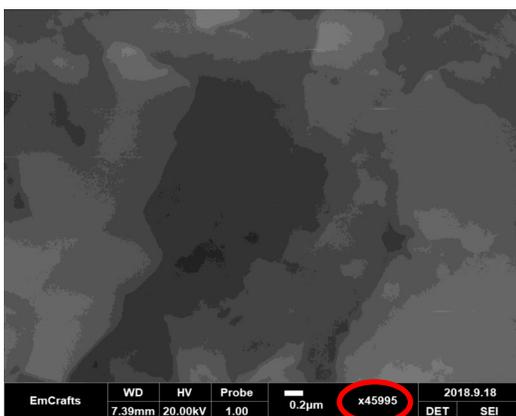
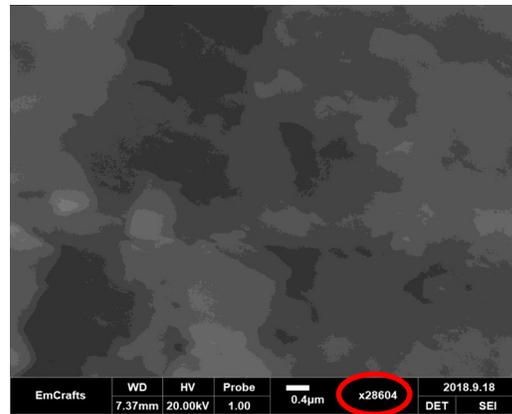
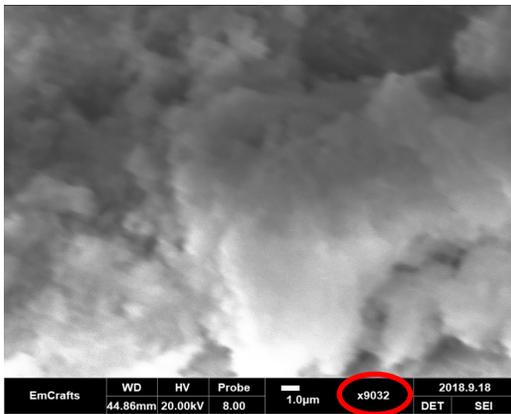
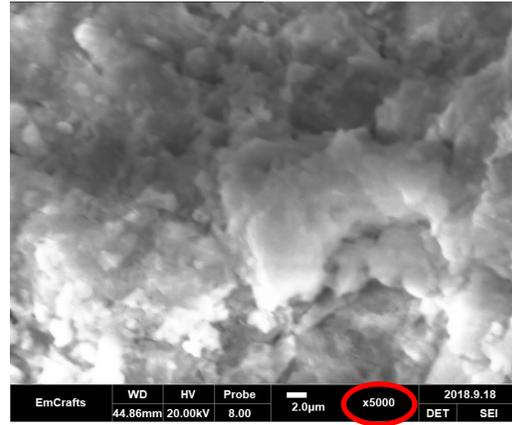
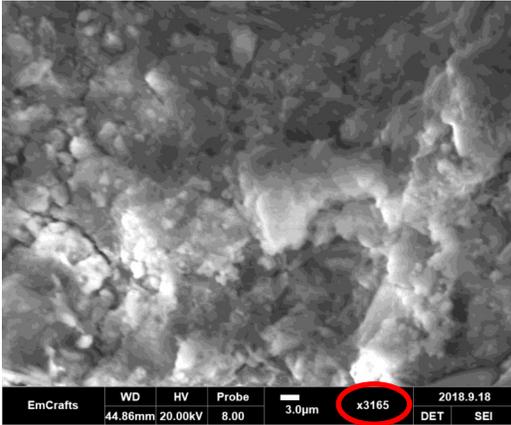


The samples shown above are non-coated silicon semiconductor samples at 20kV. Other SEMs would never be able to go above 1kV let alone 20kV. All samples run in high vac mode.

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The sample shown above is non-coated cement at 20kV. Other SEMs would never be able to go above 1kV let alone 20kV. All samples run in high vac mode without any charging.